

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components,
Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

IECQ Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 22.0003-01 Issue No.: 1 Status: Current

Additional Site to Certification: IECQ-L ULTW 22.0003 Originally Issued: 2022/01/17

Supersedes: Issue Date: 2022/01/17 Site Added: 2022/01/17

CB Reference No.: 50600440 ITL **Expiration: 2025/01/16**

MSSCORPS CO., LTD. Zhubei BRANCH

Rm. 8, 2F, No. 8, Taiyuan 2nd St., Zhubei City Hsinchu 302082 Taiwan

The organization, facilities and procedures have been assessed and found to comply with the applicable requirements for Independent Testing Laboratory organization approval, in support of the IECQ system, which is in accordance with the Basic Rules IECQ 01 and Rules of Procedure IECQ 03-6 "Independent Testing Laboratory Assessment Program Requirements" of the IEC Quality Assessment System for Electronic Components (IECQ) and applicable requirements of ISO/IEC 17025:2017 for the testing of electronic components under the IECQ.

Scope:

The provision of reliability test services of electronic components.

See attached schedule.

-- Attached Schedule: IECQ-L_ULTW_50600440 ITL. Schedule 01-17-22.pdf --

Approved by Certification Body (CB): DQS Group - DQS Taiwan Inc.

Pach Chy

8th Fl., 23, Yuan Huan West Road, Feng Yuan Dist., Taichung City

Taiwan

Authorized person:

Rock Chang





The validity of this certificate is maintained through on-going surveillance audits by the IECQ CB issuing this certificate.

This Certificate of Conformity may be suspended or withdrawn in accordance with the

Rules of Procedure of the IECQ System and its Schemes.

This certificate and any schedule(s) may only be reproduced in full.

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Schedule of Scope to Certificate of Conformity

Independent Testing Laboratory

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Schedule Number: IECQ-L ULTW 22.0003-01-S Rev No.: 1 Revision Date: 2022/01/17 Page 1 of 2

Appendix-1 (50600440 ITL) Schedule of Scope to Certificate of Approval

Test Items	Standard/Method
ESD Human Body Model (HBM)	ANSI/ESDA/JEDEC JS-001-2017
	AEC-Q100-002
	AEC-Q101-001
	MIL-STD-883
ESD Machine Model (MM)	JESD22-A115
ESD Charged Device Model (CDM)	ANSI/ESDA/JEDEC JS-002-2018
	AEC-Q100-011
	AEC-Q101-005
IC Latch-Up Test (LU)	JESD78
	AEC-Q100-004
	MIL-STD-883
Preconditioning Test	JESD22-A113
	IPC/JEDEC J-STD-020
	IPC/JEDEC J-STD-033
Acoustic Microscopy for Nonhermetic	IPC/JEDEC J-STD-035
Encapsulated Electronic Components	
High / Low Temperature Operating Teat	JESD22-A108
(HTOL / LTOL)	MIL-STD-883
	MIL-STD-750
Temperature and Bias Life Test	AEC-Q101
	AEC-Q102
	JESD22-A108
	MIL-STD-750
	MIL-STD-883
High Temperature Storage Life Test	JESD22-A103
Low Temperature Storage Life Test	JESD22-A119
Program / Erase Endurance and Data	JESD22-A117
Retention Stress Test (EDR)	AEC-Q100-005

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Early Life Failure Rate (ELFR)	JESD74
	AEC-Q100-008
	JESD85
Highly Accelerated Temperature and	JESD22-A110
Humidity Stress Test (HAST)	
Accelerated Moisture Resistance - Unbiased	JESD22-A118
HAST (UHAST) & Unbiased Autoclave (AC)	JESD22-A102
Temperature-Humidity Biased Life Test	JESD22-A101
Cycled Temperature and Humidity Biased	JESD22-A100
Life Test	MIL-STD-883
(Moisture Resistance)	
Temperature Cycling Test	JESD22-A104
	MIL-STD-883
Power and Temperature Cycling Test	JESD22-A105
Intermittent Operational Life	MIL-STD-750
Temperature Shock Test	MIL-STD-810
Moisture Sensitivity Level (MSL)	JESD22-A113
	IPC/JEDEC J-STD-020
	IPC/JEDEC J-STD-033
Thermal Stress Test	IPC/JEDEC J-STD-020
	IPC-TM-650 Method 2.6.27
Moisture and Insulation Resistance Test and	IPC-TM-650 Method 2.6.3
Conductive Anodic Filament (CAF)	IPC-TM-650 Method 2.6.25
Resistance	
Dye and Pull Test (Dye and Pry Test)	IPC-TM-650 Method 2.4.53
Solderability Test	IPC J-STD-002
	IPC J-STD-003

Technical Reviewer of DQS: Michael Chou Date: 1/17/2022

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